N-Channel Power MOSFET 600 V, 360 m Ω

Features

- 100% Avalanche Tested
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

ABSOLUTE MAXIMUM RATINGS ($T_J = 25$ °C unless otherwise noted)

Parameter			Symbol	NDD	Unit
Drain-to-Source Voltage			V _{DSS}	600	V
Gate-to-Source Volta	ıge		V _{GS}	±25	V
Continuous Drain	Steady State	T _C = 25°C	I _D	11	Α
Current R _{θJC}	State	T _C = 100°C		6.9	
Power Dissipation – $R_{\theta JC}$	Steady State	T _C = 25°C	P_{D}	114	W
Pulsed Drain Current	t _p :	= 10 μs	I _{DM}	44	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)			IS	13	Α
Single Pulse Drain-to-Source Avalanche Energy (I _D = 3.5 A)			EAS	64	mJ
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 15)			V _{ISO}	-	٧
Peak Diode Recovery (Note 1)			dv/dt	15	V/ns
Lead Temperature for Soldering Leads			T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. $I_{SD} \le 13$ A, $di/dt \le 400$ A/ μ s, $V_{DS\ peak} \le V_{(BR)DSS}$, $V_{DD} = 80\%$ $V_{(BR)DSS}$

THERMAL RESISTANCE

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{\theta JC}$	1.1	°C/W
Junction-to-Ambient Steady State (Note 3) NDD60N360U1 (Note 2) NDD60N360U1-1 (Note 2) NDD60N360U1-35G	$R_{ hetaJA}$	47 98 95	°C/W

- 2. Insertion mounted
- Surface mounted on FR4 board using 1" sq. pad size (Cu area = 1.127 in sq [2 oz] including traces)

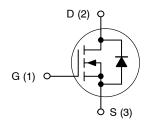


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX		
600 V	360 mΩ @ 10 V		

N-Channel MOSFET





IPAK CASE 369D



DPAK CASE 369C



IPAK CASE 369AD

MARKING AND ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 3 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

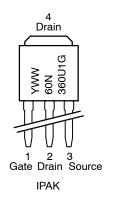
Characteristic	Symbol	Test Conditions	3	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D = 1 mA		600			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	Reference to 25°C, I _D = 1 mA			560		mV/°C
Drain-to-Source Leakage Current	I _{DSS}	V _{DS} = 600 V, V _{GS} = 0 V	T _J = 25°C			1	μΑ
			T _J = 125°C			100	1
Gate-to-Source Leakage Current	I _{GSS}	V _{GS} = ±25 V	•			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{DS} = V_{GS}, I_{D} = 250$	Αμ Ο	2	3.2	4	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	Reference to 25°C, I _D =	: 250 μA		8.6		mV/°C
Static Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 5.	5 A		320	360	mΩ
Forward Transconductance	9FS	V _{DS} = 15 V, I _D = 5.	5 A		10		S
DYNAMIC CHARACTERISTICS			-		_		
Input Capacitance	C _{iss}				790		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f$	= 1 MHz		47		1
Reverse Transfer Capacitance	C _{rss}	56 / G6 /			3.0		1
Effective output capacitance, energy related (Note 6)	C _{o(er)}	V _{GS} = 0 V, V _{DS} = 0 to 480 V			38.9		
Effective output capacitance, time related (Note 7)	C _{o(tr)}	I_D = constant, V_{GS} = 0 V, V_{DS} = 0 to 480 V			135		
Total Gate Charge	Q_{g}	$V_{DS} = 300 \text{ V}, I_D = 13 \text{ A}, V_{GS} = 10 \text{ V}$			26		nC
Gate-to-Source Charge	Q _{gs}				4.7		1
Gate-to-Drain Charge	Q _{gd}				12.9		1
Plateau Voltage	V_{GP}				5.6		V
Gate Resistance	R_{g}				4.5		Ω
RESISTIVE SWITCHING CHARACTER	ISTICS (Note 5))	•			•	•
Turn-on Delay Time	t _{d(on)}				10		ns
Rise Time	t _r	$V_{DD} = 300 \text{ V}, I_D = 13 \text{ A},$			20		1
Turn-off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V}, R_{G} = 0$	Ω΄		26		1
Fall Time	t _f				22		1
SOURCE-DRAIN DIODE CHARACTER			<u>'</u>		-	-	-
Diode Forward Voltage	V_{SD}	$I_S = 13 \text{ A}, V_{GS} = 0 \text{ V}$ $T_J = 25^{\circ}\text{C}$ $T_{J} = 100^{\circ}\text{C}$			0.93	1.6	V
					0.86		1
Reverse Recovery Time	t _{rr}	$V_{GS} = 0 \text{ V}, V_{DD} = 30 \text{ V}$ $I_{S} = 13 \text{ A}, d_{i}/d_{t} = 100 \text{ A}/\mu\text{s}$			303	1	ns
Charge Time	ta				206	1	1
Discharge Time	t _b				97		1
Reverse Recovery Charge	Q _{rr}				3.6	<u> </u>	μC

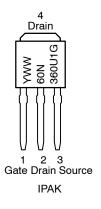
^{4.} Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.

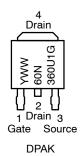
5. Switching characteristics are independent of operating junction temperatures.

6. $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$ 7. $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% $V_{(BR)DSS}$ Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

MARKING DIAGRAMS







Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NDD60N360U1-1G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N360U1-35G	IPAK (Pb-Free, Halogen-Free)	75 Units / Rail
NDD60N360U1T4G	DPAK (Pb-Free, Halogen-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL CHARACTERISTICS

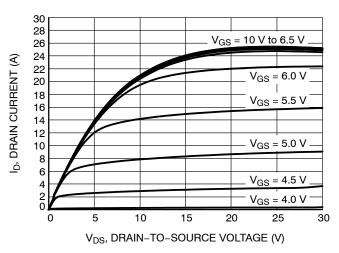


Figure 1. On-Region Characteristics

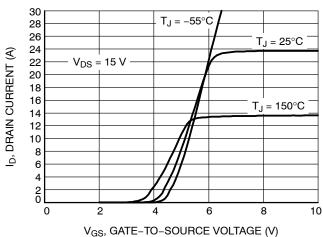


Figure 2. Transfer Characteristics

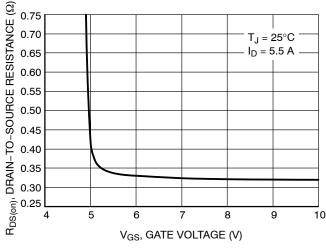


Figure 3. On-Resistance vs. Gate-to-Source Voltage

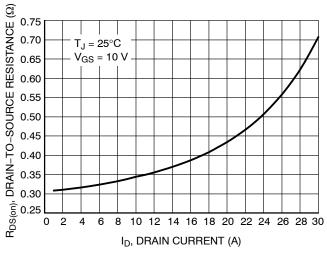


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

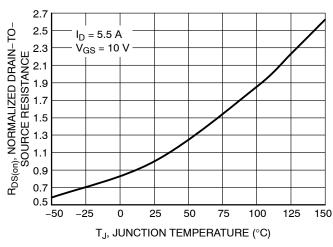


Figure 5. On–Resistance Variation with Temperature

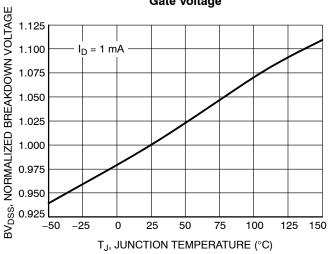


Figure 6. Breakdown Voltage Variation with Temperature

TYPICAL CHARACTERISTICS

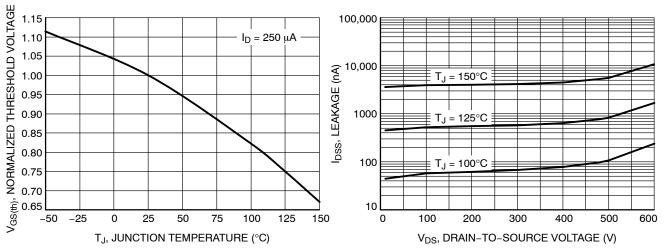


Figure 7. Threshold Voltage Variation with Temperature

Figure 8. Drain-to-Source Leakage Current vs. Voltage

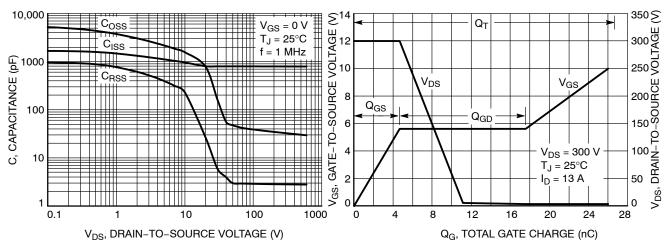


Figure 9. Capacitance Variation

Figure 10. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

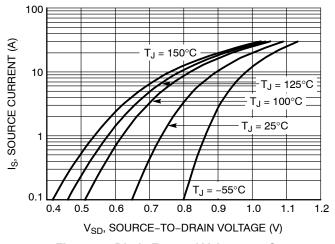


Figure 11. Diode Forward Voltage vs. Current

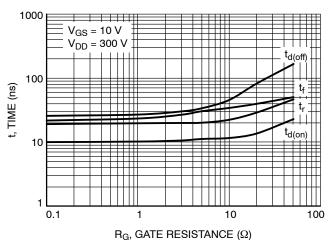


Figure 12. Resistive Switching Time Variation vs. Gate Resistance

TYPICAL CHARACTERISTICS

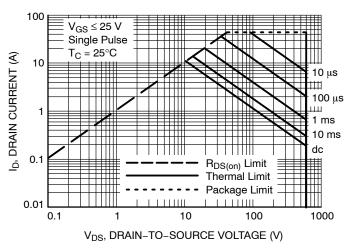


Figure 13. Maximum Rated Forward Biased Safe Operating Area NDD60N360U1

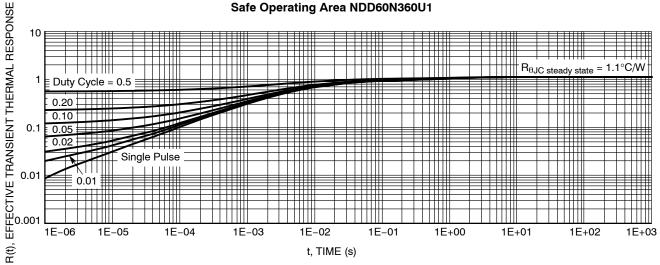
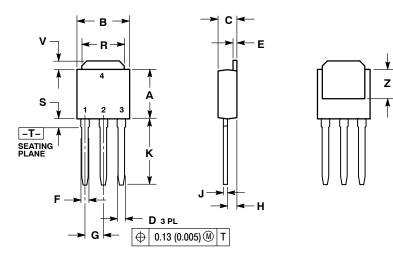


Figure 14. Thermal Impedance (Junction-to-Case) for NDD60N360U1

PACKAGE DIMENSIONS

IPAK CASE 369D-01 ISSUE C



NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.

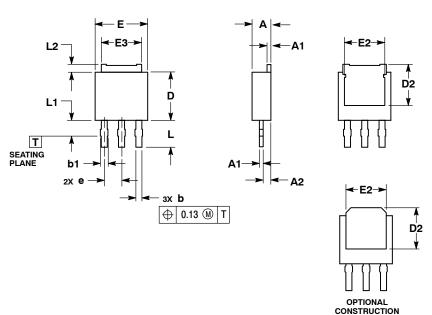
	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29 BSC	
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

STYLE 2: PIN 1. GATE

- 2. DRAIN 3. SOURCE 4. DRAIN

3.5 MM IPAK, STRAIGHT LEAD

CASE 369AD ISSUE B



NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

 3. DIMENSION 6 APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.

 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS			
DIM	MIN	MAX		
Α	2.19	2.38		
A 1	0.46	0.60		
A2	0.87	1.10		
b	0.69	0.89		
b1	0.77	1.10		
D	5.97	6.22		
D2	4.80			
Е	6.35	6.73		
E2	4.57	5.45		
E3	4.45	5.46		
е	2.28	BSC		
L	3.40	3.60		
L1		2.10		
L2	0.89	1.27		

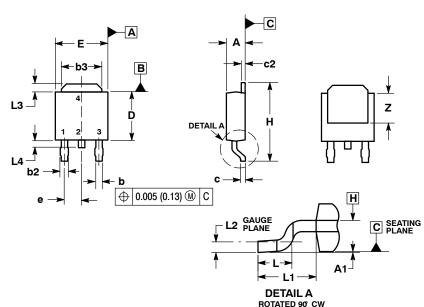
- STYLE 2: PIN 1. GATE 2. DRAIN

 - SOURCE 4. DRAIN

PACKAGE DIMENSIONS

DPAK (SINGLE GAUGE)

CASE 369C-01 ISSUE D



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M, 1994.
 CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DI-
- MENSIONS b3, L3 and Z. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.
 5. DIMENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.
 6. DATUMS A AND B ARE DETERMINED AT DATUM

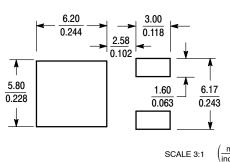
	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α	0.086	0.094	2.18	2.38	
A1	0.000	0.005	0.00	0.13	
b	0.025	0.035	0.63	0.89	
b2	0.030	0.045	0.76	1.14	
b3	0.180	0.215	4.57	5.46	
С	0.018	0.024	0.46	0.61	
c2	0.018	0.024	0.46	0.61	
D	0.235	0.245	5.97	6.22	
E	0.250	0.265	6.35	6.73	
е	0.090	BSC	2.29	BSC	
Н	0.370	0.410	9.40	10.41	
L	0.055	0.070	1.40	1.78	
L1	0.108	0.108 REF		REF	
L2	0.020 BSC		0.51 BSC		
L3	0.035	0.050	0.89	1.27	
L4		0.040		1.01	
Z	0.155		3.93		

STYLE 2:

PIN 1. GATE 2. DRAIN

- 3. SOURCE 4. DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking, pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada **Fax**: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative